


<b>Search Notes</b> 	<b>Application/Control No.</b> 10597198	<b>Applicant(s)/Patent Under Reexamination</b> BEIER ET AL.
	<b>Examiner</b> SANG Y PAIK	<b>Art Unit</b> 3742

SEARCHED			
Class	Subclass	Date	Examiner
219	443.1-468.2, 494, 497, 502	9/8/09	sp
374	120-132	9/8/09	sp
updated		3/12/10	sp

SEARCH NOTES			
Search Notes		Date	Examiner
east searched		9/8/09	sp

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

--	--